

# MS-100D DIE Sorting Tester



# Innovative DIE Sorting Solution

- MS-100D is cost effective, high performing DIE Sorting solution. With changeable probe card MS-100D is able to test various DRAM DIE: LPDDR4/3/2, DDR4/3. So far we already provided customer below DIE solution:

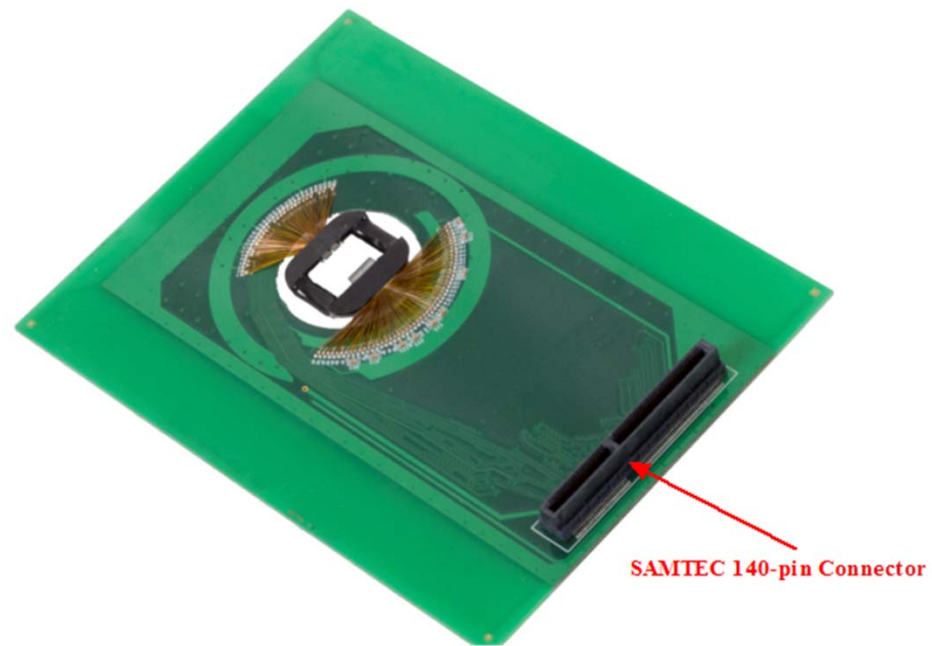
DRAM Type	DIE
LPDDR2	U80M, 2E0E, 2C0E
LPDDR3	2E0F, V91M, V01M, V9AM
LPDDR4	Z01M, Z11M



# Fast Development Time

- MS-100D is FPGA\_Based tester, CST has more than 30 years experience on memory testing, and has memory controller for almost all DRAM devices on the market.
- Simple Probe Card design - only probe and connector
- Lead-time for a new DIE is 4-6 weeks

LPDDR3 2E0F Probe Card



# Fast test time, high FT good percentage

DIE Type	DIE Sorting Test Time	FT Good Percentage
U80M (4Gb)	10 Seconds	92-95%
2E0E (4Gb)	10 Seconds	92-95%
2C0E (4Gb)	10 Seconds	92-95%
2E0F (4Gb)	17 seconds	92-95%
V91M (8Gb)	34 seconds	92-95%
V01M (8Gb)	34 seconds	92-95%
V9AM (6Gb)	26 seconds	92-95%
Z01M (8Gb)	34 seconds	92-95%
Z11M (8Gb)	54 seconds	92-95%

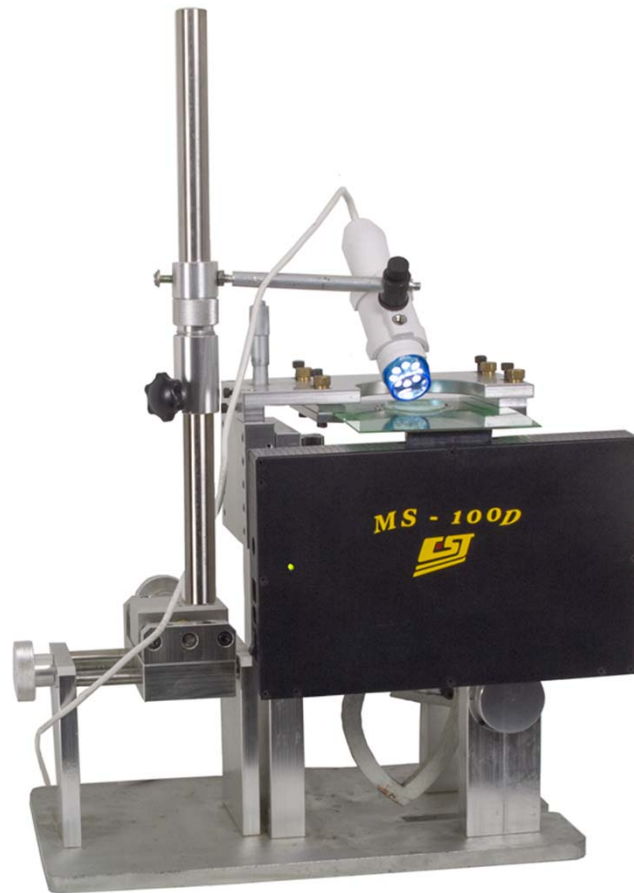


# Support DQ BIN Sorting

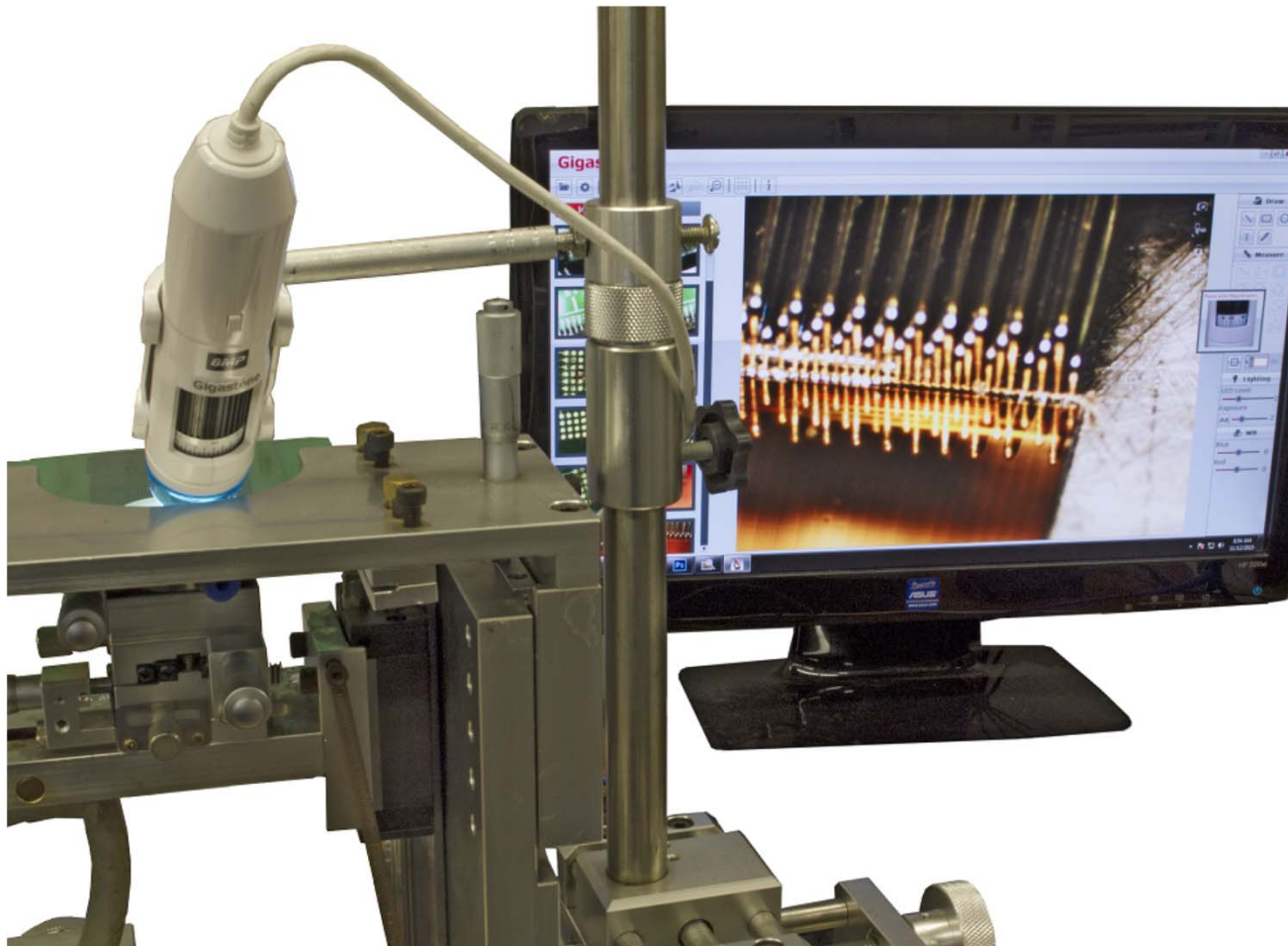
A(DQ0-DQ7); B(DQ8-DQ15);C(DQ16-DQ23);D(DQ24-DQ31);	
BIN	Description
1	AB : PASS ; CD : FAIL
2	AB : FAIL ; CD : PASS
3	AC : PASS ; BD : FAIL
4	AC :FAIL ; BD : PASS
5	AD: Pass ; BC: FAIL
6	AD::FAIL , BC: PASS



Small form-factor size and works with different probe card station

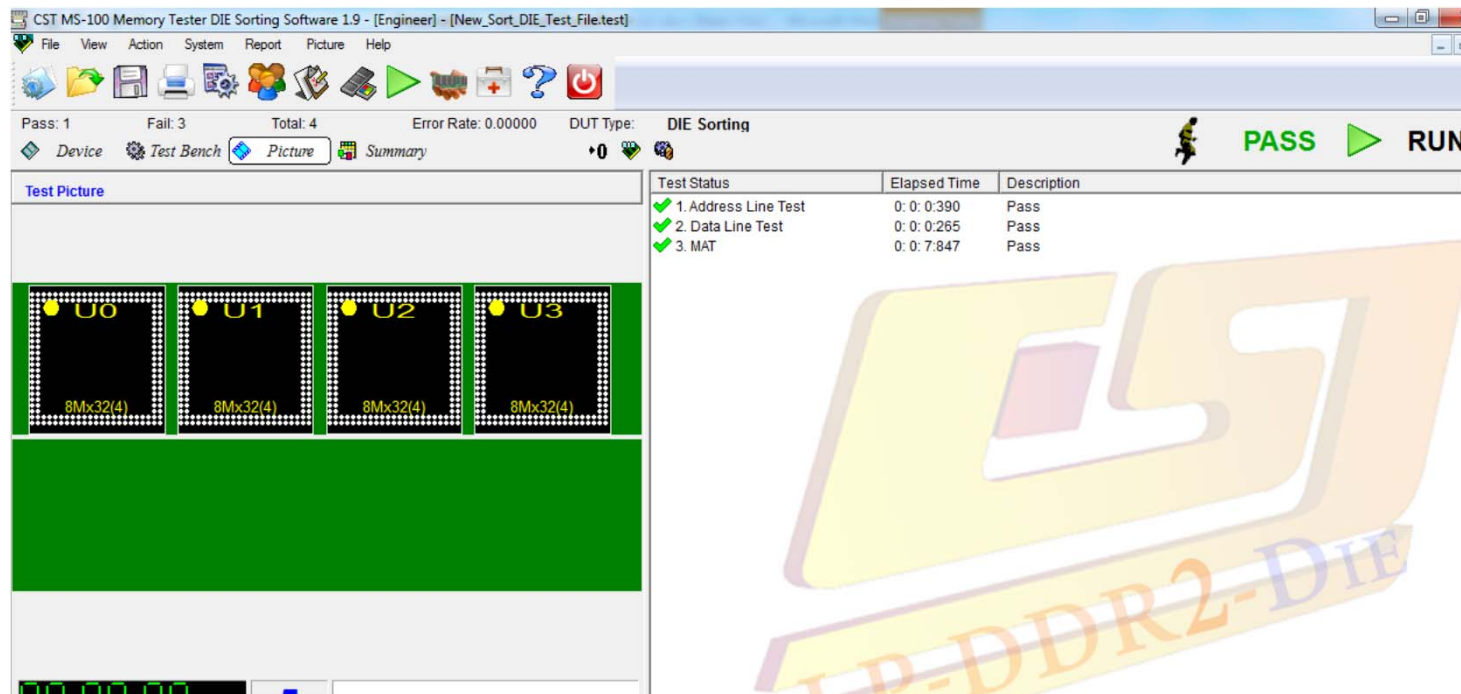


# Easy to align Probe & DIE PAD



# Easy to us

- MS-100D has Start Button, 1-click-to-run
- Detail & clear result display



The screenshot displays the CST MS-100 Memory Tester DIE Sorting Software 1.9 interface. The window title is "CST MS-100 Memory Tester DIE Sorting Software 1.9 - [Engineer] - [New\_Sort\_DIE\_Test\_File.test]". The menu bar includes File, View, Action, System, Report, Picture, and Help. The toolbar contains various icons for file operations and testing. The status bar shows "Pass: 1", "Fail: 3", "Total: 4", "Error Rate: 0.00000", and "DUT Type: DIE Sorting". A large green "PASS" button and a "RUN" button are visible. The "Test Picture" section shows four die images labeled U0, U1, U2, and U3, each with "8Mx32(4)" below it. The "Test Status" table shows the following results:

Test Status	Elapsed Time	Description
✓ 1. Address Line Test	0: 0: 0.390	Pass
✓ 2. Data Line Test	0: 0: 0.265	Pass
✓ 3. MAT	0: 0: 7.847	Pass





For further information, visit [www.simmtester.com](http://www.simmtester.com)  
or call our Sales at (972)241-2662 x312.

Address: 2336 Lu Field Road , Dallas, Texas 75229 USA

Tel : (972)-241-2662

Fax : (972)-241-2661

Email : [info@simmtester.com](mailto:info@simmtester.com)

